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Table of Contents

Message from the General Chairman	xi
Message from the Technical Program Chair.....	xii
IEEE AUTOTEST 2014 Committee.....	xiii
IEEE AUTOTEST 2014 Sponsors.....	xiv
IEEE AUTOTEST 2014 Promotional Partners.....	xv
IEEE AUTOTEST 2014 Promotional Partners.....	xvi
Awards.....	xvii
Featured Speaker.....	xviii
Tutorials Program.....	xix
Master Schedule	xxiv
Tutorials Program Schedule	xxiv
IEEE AUTOTEST 2015 Call for Papers	xxv

Tuesday, 16 September, 2014

Automatic Test Systems 1

SESSION B1

3:00 PM - 5:00 PM

Session Chair: Michael Seavey (Northrop Grumman, USA)

ATE system level calibration and its impact on cost, quality and schedule	1
--	----------

Lee Nichols (Keysight Technologies, USA)

Duane Lowenstein (Keysight Technologies, USA)

Joe LaGrotta (Keysight Technologies, Inc., USA)

Development of Attitude Control System Electric Simulators for Microsatellite	8
--	----------

Guangquan Zhao (Harbin Institute of Technology, P.R. China)

Jin Yi (Harbin Institute of Technology, P.R. China)

Wei Xu (Chinese Academy of Sciences, P.R. China)

Sirui Xing (Chinese Academy of Sciences, P.R. China)

The CMA Program: an Example of Support and Service at the Customer's Air Base
--

using LM-STAR®	12
-----------------------------	-----------

Steven J O'Donnell (Lockheed Martin, USA)

Paolo Anzile (Selex ES, Italy)

Testing Ultra-Precise, Strategic-Grade Instrumentation Using a Flexible and Modular
--

Common Test Station Architecture	19
---	-----------

Matthew Van Laethem (Draper Laboratory, USA)

Mitch Leammukda (Draper Laboratory, USA)

Peter Castelli (Draper Laboratory, USA)

Patrick Dunbeck (Bloomy Controls, USA)

Test Technology 1

SESSION C1

3:00 PM - 5:00 PM

Session Chair: Jerry Murdock (Boeing, USA)

The Behavioral Approach to Diagnostics of Cyber-Physical Systems..... 26

Victor Skormin (Binghamton University, USA)

Andrey Dolgikh (Binghamton University, USA)

Zachary Birnbaum (Binghamton University, USA)

Fuzzy PI Modification for Decision Making Simulation on a Conveyor 31

Jhonny de Sá Rodrigues (Universidad Simón Bolívar, Venezuela)

Joaquín Santos (University Simon Bolivar, Venezuela)

Research on Fault Diagnosis Risk based on Electromagnetic Interference B#5

Wang Gang (National University of Defense Technology, P.R. China)

Qiu Jing (National University of Defense Technology, P.R. China)

Guanjun Liu (National University of Defense Technology, P.R. China)

Kehong Lv (National University of Defense Technology, P.R. China)

Zhao Chenxu (National University of Defense Technology, P.R. China)

Efficient Testing of Simulation V&V for Closed-Loop Operations 44

Alan Campbell (Draper Laboratory, USA)

Dianna Velez (Draper Laboratory, USA)

A sub-Nyquist sampling spectrum sensing system based on PXI bus for multiband signals 52

Jingchao Zhang (Harbin Institute of Technology, P.R. China)

Tingting Yao (Harbin Institute of Technology, P.R. China)

Ning Fu (Harbin Institute of Technology, P.R. China)

Qiao Li-yan (Harbin Institute of Technology, P.R. China)

Wang Liu (Harbin Institute of Technology, P.R. China)

Instrumentation 1

SESSION D1

3:00 PM - 5:00 PM

Session Chair: Bob Helsel (VXIbus Consortium, PXI Systems Alliance, LXI Consortium, and AXIe Consortium, USA)

Development of High-Speed Data Acquisition Card based on PXI Express Bus..... 57

Wang Liu (Harbin Institute of Technology, P.R. China)

Lianzhong Wang (Harbin Institute of Technology, P.R. China)

Ning Fu (Harbin Institute of Technology, P.R. China)

Zhiming Yang (Harbin Institute of Technology, P.R. China)

Yang Yu (Harbin Institute of Technology, P.R. China)

Qiao Li-yan (Harbin Institute of Technology, P.R. China)

Test Requirements: Selecting the Optimal AC Power Source Technology

for your Application: Linear or Switch Mode Technology considerations and trade-offs 64

Herman van Eijkelenburg (Pacific Power Source, Inc, USA)

Bruce Rouser (Pacific Power Source, Inc., USA)

Bill Monagle (Pacific Power Source, Inc., USA)

The Pitfalls of Instrument Compatibility	69
---	-----------

Mike Haney (Teradyne, Inc., USA)

Linearized Adaptation of Non-Linear Post Conversion Correction for TIADCs: A Behavioral Model Study	78
--	-----------

Charna Parkey (University of Central Florida, USA)

Wasfy Mikhael (University of Central Florida, USA)

Wednesday, 17 September, 2014

Automatic Test Systems 2

SESSION B2

10:30 AM - 12:00 PM

Session Chair: Michael Dewey (Marvin Test Solutions, USA)

Integrated Solutions for Radio Test ATE: Targeting each level of maintenance	81
---	-----------

Michael S Caulfield (Astronics Test Systems, USA)

Charna Parkey (Astronics Test Systems, USA)

Ian Williams (Astronics Test Systems, USA)

A Next Generation ATE Switching Solution: As applied by Rockwell Collins	87
---	-----------

Robert Waldeck (Giga-tronics Incorporated, USA)

Robert Dahl (Rockwell Collins, USA)

Test Equipment Refresh For High Reliability, Mission Critical Hardware	96
---	-----------

Sean Buckley (Draper Lab, USA)

Automatic Hybrid Test Stations for Software-Defined Radios	101
---	------------

Aydin Guney (ASELSAN Inc. & Middle East Technical University, Turkey)

Emrah Gingir (ASELSAN Inc. & Middle East Technical University, Turkey)

Unal Uluçay (ASELSAN Inc., Turkey)

Design for Test

SESSION C2

10:30 AM - 12:00 PM

Session Chair: Mike Ellis (Retired, USA)

Fiddly Fussy Finicky Failures can Deviously Evoke Detection.....	108
---	------------

Larry V. Kirkland (WesTest Engineering, USA)

Integrated Design and Testability Modeling for System Level BIT	B#5
--	------------

Wang Gang (National University of Defense Technology, P.R. China)

Qiu Jing (National University of Defense Technology, P.R. China)

Guanjun Liu (National University of Defense Technology, P.R. China)

Kehong Lv (National University of Defense Technology, P.R. China)

Zhao Chenxu (National University of Defense Technology, P.R. China)

A Testability Growth Model and Its Application	121
---	------------

Chenxu Zhao (National University of Defense Technology & University of Connecticut, P.R. China)

Krishna Pattipati (University of Connecticut, USA)

Jing Qiu (National University of Defense Technology, P.R. China)

Guanjun Liu (National University of Defense Technology, P.R. China)

Kehong Lu (National University of Defense Technology & Key Laboratory of Science and Technology on Integrated Logistics Support, P.R. China)

The True Nature of False Alarms.....	129
<i>Louis Y. Ungar (A.T.E. Solutions, Inc., USA)</i>	
Instrumentation 2	
SESSION D2	
10:30 AM - 12:00 PM	
Session Chair: Larry Kent (Draper Laboratory, USA)	
Using FPGA as Synthetic Instrumentation in Automated Test Sets: Benefits and Examples	136
<i>Madaline Dziuk (CACI INC.-Federal, USA)</i>	
Highly Synchronized, Simultaneous, High-Speed 24-bit Data Acquisition of Triaxial MEMS Accelerometers for Monitoring a Real World Civil Structure	142
<i>Brianna Klingensmith (Draper Laboratory, USA)</i>	
<i>Michael Feng (Draper Laboratory, USA)</i>	
<i>Thomas Campbell (Draper Laboratory, USA)</i>	
<i>Reza Mohammadi Ghazi (Massachusetts Institute of Technology, USA)</i>	
<i>Oral Buyukozturk (Massachusetts Institute of Technology, USA)</i>	
Possible alternatives to overcoming speed limitations using Synthetic Instruments signal analysis architecture.....	150
<i>John Stratton (Keysight Technologies, USA)</i>	
Firmware Development Methodologies for Synthetic Test Instrumentation.....	153
<i>Michael Fluet (Teradyne, Inc., USA)</i>	
<i>Joseph Manzi, III (Teradyne, Inc., USA)</i>	
Automatic Test Systems 3	
SESSION B3	
1:30 PM - 3:00 PM	
Session Chair: Louis Ungar (A.T.E. Solutions, Inc., USA)	
Automatic test system for large unmanned aerial vehicle	159
<i>Deng Dawei (Beihang University, P.R. China)</i>	
<i>Li Baoan (Beihang University, P.R. China)</i>	
Portable Automated Test Station: An Engineering-Design Partnership to Replace Obsolete Test Systems	163
<i>Benjamin D Chase (USAF & AFMC 309th Software Maintenance Group, USA)</i>	
Expanding Emulation from Test to Create Realistic Virtual Training Environments.....	168
<i>Daniel A Tagliente (US Army, ARDEC, USA)</i>	
<i>Charles Lyding (US Army, ARDEC, USA)</i>	
<i>Joshua Zawislak (US Army, ARDEC, USA)</i>	
<i>Derek Marston (US Army, USA)</i>	
The Research on a New Implementation Scheme of the Portable General Purpose Automatic Test System	173
<i>Yonghui Xu (Harbin Institute of Technology, P.R. China)</i>	
<i>Jihui Zhang (Harbin Institute of Technology, P.R. China)</i>	
<i>Xiaodong Liu (Harbin Institute of Technology, P.R. China)</i>	

Test Technology 2

SESSION C3

1:30 PM - 3:00 PM

Session Chair: Dean Matsuura (Teradyne Inc., USA)

Measurement of Field Complex Noise Using a Novel Acoustic Detection System..... 177

Jun Qin (Southern Illinois University Carbondale, USA)

Pengfei Sun (Southern Illinois University Carbondale, USA)

Jacob Walker (Southern Illinois University Carbondale, USA)

Analysis of Impulse Noise Based on Wavelet Transform for Military Applications..... 183

Pengfei Sun (Southern Illinois University Carbondale, USA)

Jun Qin (Southern Illinois University Carbondale, USA)

IEEE P1505.3 Universal Test Interface Framework and Pin Configuration for Portable/Bench Top Test Requirements Utilizing IEEE 1505 Receiver Fixture Interface Standard 188

Michael J Stora (System Interconnect Technologies, USA)

Robert Spinner (Advanced Testing Technologies, Inc. & ATTI, USA)

Stephen Mann (BCO, Inc, USA)

George Isabella (BAE Systems, USA)

David Droste (CGI Federal, USA)

Using Continuous-Time Bayesian Networks for Standards-Based Diagnostics and Prognostics 198

Logan Perreault (Montana State University, USA)

John W. Sheppard (Montana State University, USA)

Houston King (Montana State University, USA)

Liessman Sturlaugson (Montana State University, USA)

Test Program Set Development 1

SESSION D3

1:30 PM - 3:00 PM

Session Chair: Noe Duarte (Systems Integration & Test, USA)

Automated TPS Conversion 205

Joe Headrick (Lockheed Martin, USA)

Teresa P Lopes (Teradyne, Inc., USA)

Gilberto García (NAVAIR Jacksonville, FL, USA)

Michael Rutledge (IEEE & Astronics Test Systems, USA)

Automated HITS to LASAR Translation: Application, Evaluation, Opportunities, and Obstacles 209

Jeremy Shannon (76th Software Maintenance Group, Tinker Air Force Base, USA)

Christopher Richardson (76th Software Maintenance Group, Tinker Air Force Base, USA)

John Dyer (University of Oklahoma & MARIP, LLC, USA)

Development of a Test Program Set on the Consolidated Automated Support System for a Redesigned AN/APG-73 Radar Receiver Shop Replaceable Assembly 218

Gregory T Fedorak (Raytheon Canada Limited, Canada)

Creating an Expandable Test Executive for Automated Testing with LabVIEW Object-Oriented Programming (LVOOP) 221

Daniel Coons (Technology Service Corporation, USA)

Net-Centric Technologies

SESSION B4

3:30 PM - 5:00 PM

Session Chair: Conchetta Thompson (Boeing, USA)

An AI-ESTATE Conformant Interface for Net-Centric Diagnostic and Prognostic Reasoning..... 226

Houston King (Montana State University, USA)

Nathan Fortier (Montana State University, USA)

John W. Sheppard (Montana State University, USA)

The Unique Challenges of Testing Specialized Network-Based Data Acquisition Systems 233

Stephen Kilpatrick (Southwest Research Institute, USA)

Todd Newton (Southwest Research Institute, USA)

Study on Performance Monitoring and Analysis for Networked Test System B#5

Zhaoqing Liu (Harbin Institute of Technology, P.R. China)

Peng Li (Harbin Institute of Technology, P.R. China)

Qiao Li-yan (Harbin Institute of Technology, P.R. China)

Using Commercial Web Services to Build Automated Test Equipment Cloud Based Applications..... 246

Dale Reitze (Northrop Grumman, USA)

Advanced Health Management 1

SESSION C4

3:30 PM - 5:00 PM

Session Chair: Eric Nicks (Boeing, USA)

Lightweight, Low-cost and Flexible Flight Data Monitoring 251

Brad W. Zarikoff (Latitude Technologies Corporation, Canada)

David Martin (Latitude Technologies Corporation, Canada)

Mark Insley (Latitude Technologies Corporation, Canada)

Integrated Battery Fuel Gauge and Optimal Charger..... 260

Bharath Pattipati (University of Connecticut & Systems & Optimization Lab, USA)

Balakumar Balasingam (University of Connecticut, Canada)

Ali Abdollahi (University of Connecticut, USA)

Gopi Avvari (University of Connecticut, USA)

Krishna Pattipati (University of Connecticut, USA)

Yaakov Bar-Shalom (University of Connecticut, USA)

Using Temporal Causal Models to Isolate Failures in Power System Protection Devices 270

Nagabhushan Mahadevan (Vanderbilt University, USA)

Abhishek Dubey (Vanderbilt University, USA)

Gabor Karsai (Vanderbilt University/ISIS, USA)

A Testbed for Implementing Prognostic Methodologies on Cryogenic Propellant Loading Systems 280

Chetan Kulkarni (NASA Ames Research Centre, USA)

Matthew Daigle (NASA Ames Research Centre, USA)

George Gorospe (NASA Ames Research Centre, USA)

Kai F. Goebel (NASA Ames Research Centre, USA)

RF Test Technology

SESSION D4

3:30 PM - 5:00 PM

Session Chair: Jeff Murrill (Northrop Grumman, USA)

Software Defined Radio as a solution to testing RF Avionics..... 290

Greg R. Shaw (CertTech LLC, USA)

Jerry Lopato (National Instruments, USA)

A Low Cost HF Direction Finding Antenna Array Simulator for Verification of HF-DF Receivers 293

Neriman Ergezer (ASELSAN Inc., Turkey)

Halil Nayir (ASELSAN Inc., Turkey)

Making Repeatable RF and microwave VNA Measurements from R&D

to at platform for weapon systems..... 298

John Stratton (Keysight Technologies, Inc., USA)

Thursday, 18 September, 2014

Automatic Test Systems 4

SESSION B5

8:00 AM - 10:00 AM

Session Chair: Dale Reitze (Northrop Grumman, USA)

Using a Common Test Infrastructure for Standardized Interfaces 301

Veysel Yücesoy (ASELSAN Inc., Turkey)

Fatih Demir (ASELSAN Inc., Turkey)

Deniz Durusu (ASELSAN Inc., Turkey)

Techniques and Lessons Learned from a Rapid Response Deployment

of an Automated Test System 309

Mitch Leammukda (Draper Laboratory, USA)

Brandon Jalbert (Draper Laboratory, USA)

Ari Lax (Draper Laboratory, USA)

Addressing Legacy ATE System Requirements with PXI..... 314

Michael J Dewey (Marvin Test Solutions, USA)

Test Technology 3

SESSION C5

8:00 AM - 10:00 AM

Session Chair: Chetan Kulkarni (NASA Ames Research Center, USA)

Application of Active Microwave Thermography to Inspection of Carbon Fiber

Reinforced Composites 318

Ali Foudazi (Missouri University of Science and Technology, USA)

Mohammad Tayeb Ghasr (Missouri University of Science and Technology, USA)

Kristen M Donnell (Missouri University of Science and Technology, USA)

Real Time Scheduling of Multiple Executions of Tasks to Achieve Fault

Tolerance in Multiprocessor Systems 323

Hussain Al-Asaad (University of California, Davis, USA)

Using Statistical Analysis Methods to Predict Switching Stability	329
<i>Carl Liebmann, Jr. (Northrop Grumman, USA)</i>	
<i>Martin Diorio (Northrop Grumman Corporation, USA)</i>	
Test Methodology For A GPS Denied Body-Worn Tracking System	<i>paper not available at time of production</i>
<i>Troy Jones (Draper Laboratory, USA)</i>	
<i>Mitch Leammukda (Draper Laboratory, USA)</i>	
<i>Evan Doyle (Yale University, USA)</i>	
Instrumentation 3	
SESSION D5	
8:00 AM - 10:00 AM	
Session Chair: Robert Hoover (Teradyne, Inc., USA)	
The Research on the Design and Application of a New Configurable Test Instrument.....	342
<i>Yonghui Xu (Harbin Institute of Technology, P.R. China)</i>	
<i>Jihui Zhang (Harbin Institute of Technology, P.R. China)</i>	
<i>Xiaodong Liu (Harbin Institute of Technology, P.R. China)</i>	
Next Generation Synthetic Instruments.....	346
<i>William Driver (National Instruments, USA)</i>	
Test Program Set Development 2	
SESSION D6	
10:30 AM - 12:00 PM	
Session Chair: Peter Castelli (Draper Laboratory, USA)	
Application of IEEE Standards and ATML in TPS Development for Ministry Of Defence UK	350
<i>Steven Kelly (Ministry of Defence, United Kingdom)</i>	
A Flexible Software Framework with Dynamic Expansible Signals	355
<i>Shuangcheng Niu (Naval Aeronautical Engineering Institute of China & NAEI, P.R. China)</i>	
<i>Aiqiang Xu (Navy Aeronautic Engineering Institute, P.R. China)</i>	
<i>Zhenyu Song (Navy Aeronautic Engineering Institute, P.R. China)</i>	
Efficient Algorithm for Test Vector Decompression Using an Embedded Processor	360
<i>Kamran Saleem (The University of Texas at Austin, USA)</i>	
<i>Nur Touba (The University of Texas at Austin, USA)</i>	
Upgrading Obsolete Integrated Circuits using Field Programmable Gate Arrays (FPGA)	365
<i>Conchetta Thompson (Boeing, USA)</i>	
Adaptable Test Program Set Development Ensures an Adept Test Program.....	372
<i>Larry V. Kirkland (WesTest Engineering, USA)</i>	
AUTHOR INDEX	378